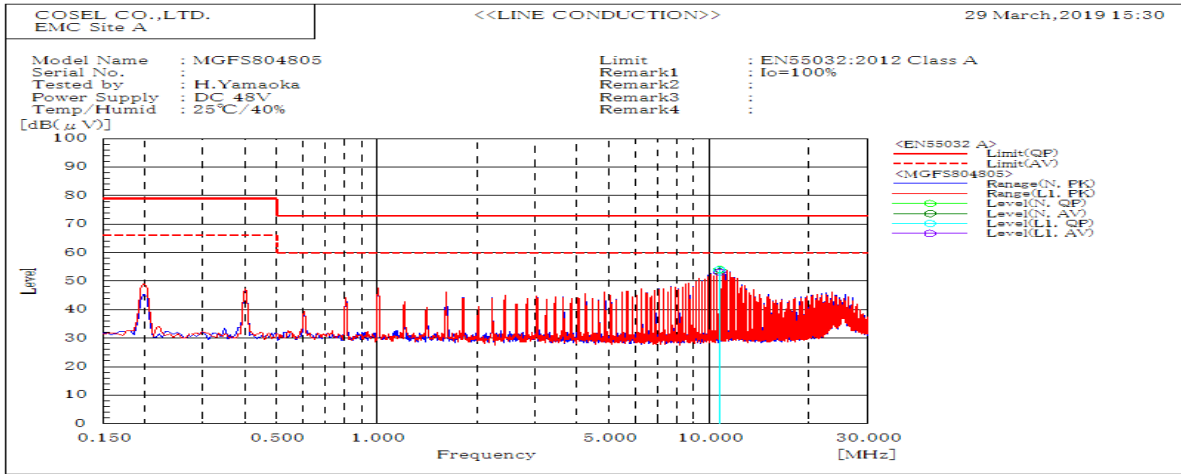
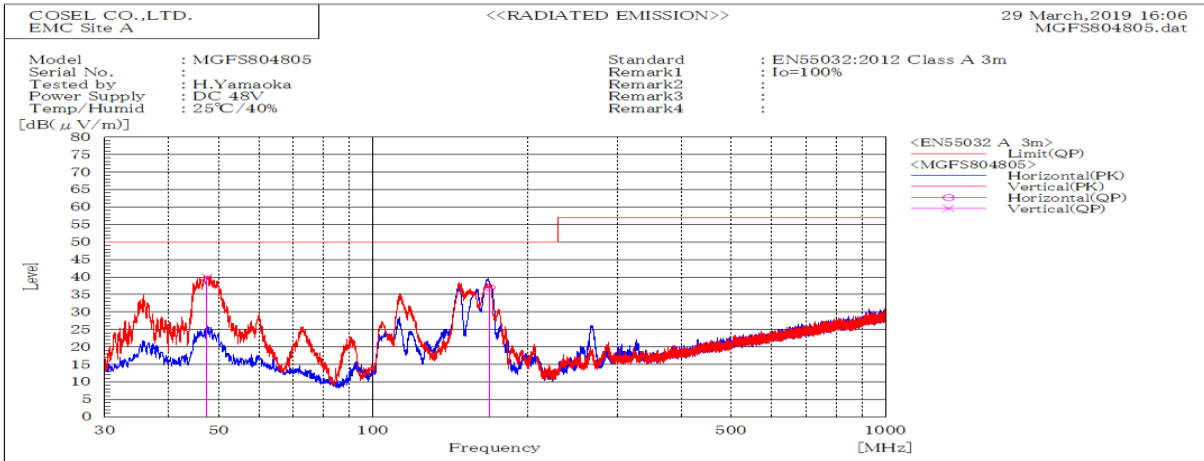


DATA SHEET		Date	23-Apr-19
Model	MGFS804805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka



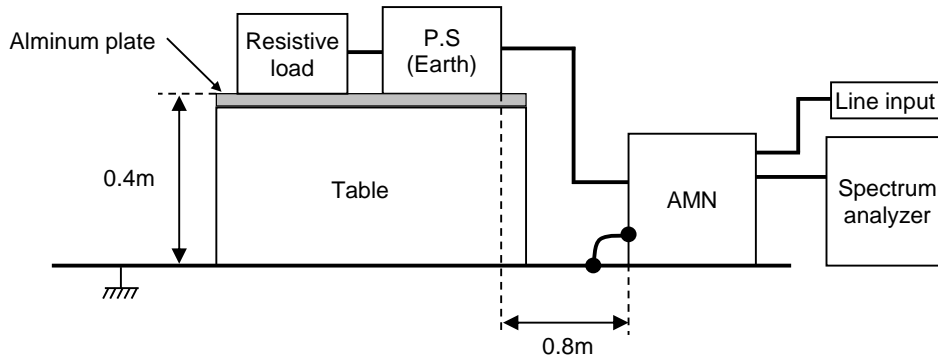
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
		10.729	L1	53.9	53.2	73	60		
10.725	N	54.1	53.3	73	60	18.9	6.7	Pass	



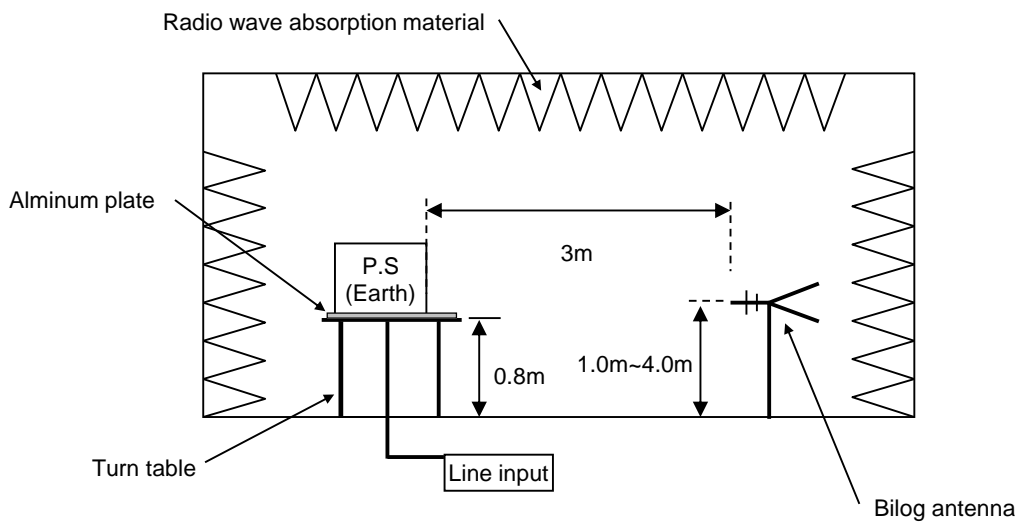
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
168.807	H	Stable	36.9	50	13.1	Pass	182.1	351.3	
47.504	V	Stable	40	50	10	Pass	100.2	34.6	

DATA SHEET		Date	23-Apr-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

**1. Line conduction**



**2. Radiated emission**



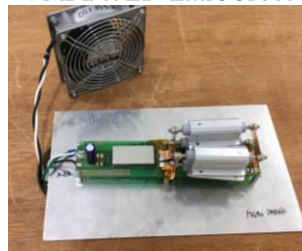
**Conditions**

Test : EMI  
 Model Name : MGFS80□□

○Photographs of Test Set-Up  
**LINE CONDUCTION**



**RADIATED EMISSION**



○Testing circuitry

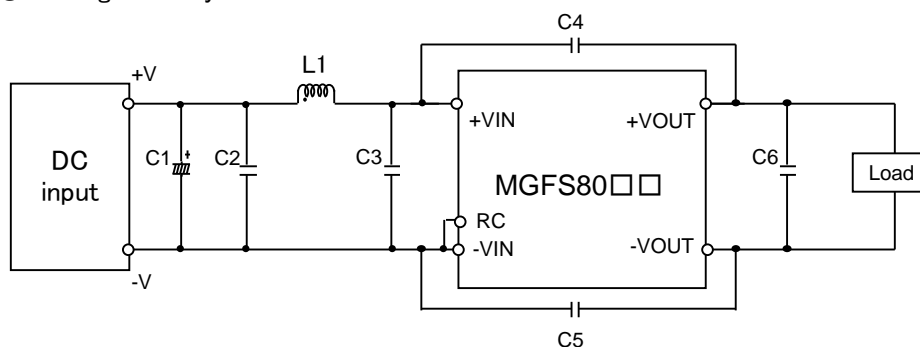


Fig.1 Testing circuitry

- C1 : MGFS8024□□ 63V 470  $\mu$ F Electrolytic capacitor (ELXseries NIPPON CHEMI-CON)  
 MGFS8048□□ 100V 220  $\mu$ F Electrolytic capacitor (KYseries NIPPON CHEMI-CON)
- C2 : MGFS8024□□ 50V 10  $\mu$ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)  
 MGFS8048□□ 100V 4.7  $\mu$ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C3 : MGFS8024□□ 50V 10  $\mu$ F Ceramic capacitor (GRM32ER71H106K MURATA MANUFACTURING)  
 MGFS8048□□ 100V 4.7  $\mu$ F Ceramic capacitor (HMK325C7475K TAIYOU YUDEN)
- C4,C5 : MGFS8024□□ 2kV 2200pF Ceramic capacitor (GR443QR73D222KW01 MURATA MANUFACTURING)  
 MGFS8048□□ 2kV 3300pF Ceramic capacitor (GR443QR73D332KW01 MURATA MANUFACTURING)
- C6 : MGFS8024□□ 25V 22  $\mu$ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)  
 MGFS8048□□ 25V 22  $\mu$ F Ceramic capacitor (GRM32ER71E226K MURATA MANUFACTURING)
- L1 : MGFS8024□□ 12.0A 1.8  $\mu$ H Inductor (SRP7050TA-1R8M BOURNS)  
 MGFS8048□□ 8.0A 3.3  $\mu$ H Inductor (SRP7050TA-3R3M BOURNS)